

Calibration standard for high-resolution X-Ray Diffraction

Art. ID	NIST-2000
Unit	1 block
Deliverydetails	No Dangerous Good /not restricted

Description

This Standard Reference Material® (SRM®) provides the high-resolution X-ray diffraction (HRXRD) community with International System of Units (SI) traceable Si (220) d-spacing in transmission, surface-to-crystal-plane wafer miscut, and surface-to-Si (004) Bragg angle in reflection for our reference wavelength. A unit of NIST-2000 consists of 25 mm × 25 mm × 0.725 mm double-polished (100)-oriented, single-crystal Si specimens with a nominal 50 nm Si_{0.85}Ge_{0.15} epitaxial layer and 25 nm Si cap. These certified values can be used to calibrate HRXRD instrumentation.

Text/Information	Analyte/Parameter	CAS number	Concentration/Value	Unit	Method	Source
Please ask for current certificate						